



**Fault Diagnosis and
Tolerance in Cryptography**

8th Workshop on Fault Diagnosis and Tolerance in Cryptography

General Co-chairs:

Luca Breveglieri¹ and Israel Koren²

Program Co-chairs:

Junko Takahashi³ and Sylvain Guilley⁴

Invited papers Chair: David Naccache⁵

¹ Politecnico di Milano, Milano, Italy

² University of Massachusetts, Amherst, USA

³ NTT Information Laboratories, Tokyo, Japan

⁴ Telecom ParisTech, Paris, France

⁵ École Normale Supérieure de Paris, France

FDTC 2011

- In cooperation with IACR
- sponsored by
 - Politecnico di Milano
 - University of Massachusetts at Amherst
 - TELECOM-ParisTech
- Proceedings by the IEEE CS Press
 - Included in the IEEE Digital Library (IEEE Explore)

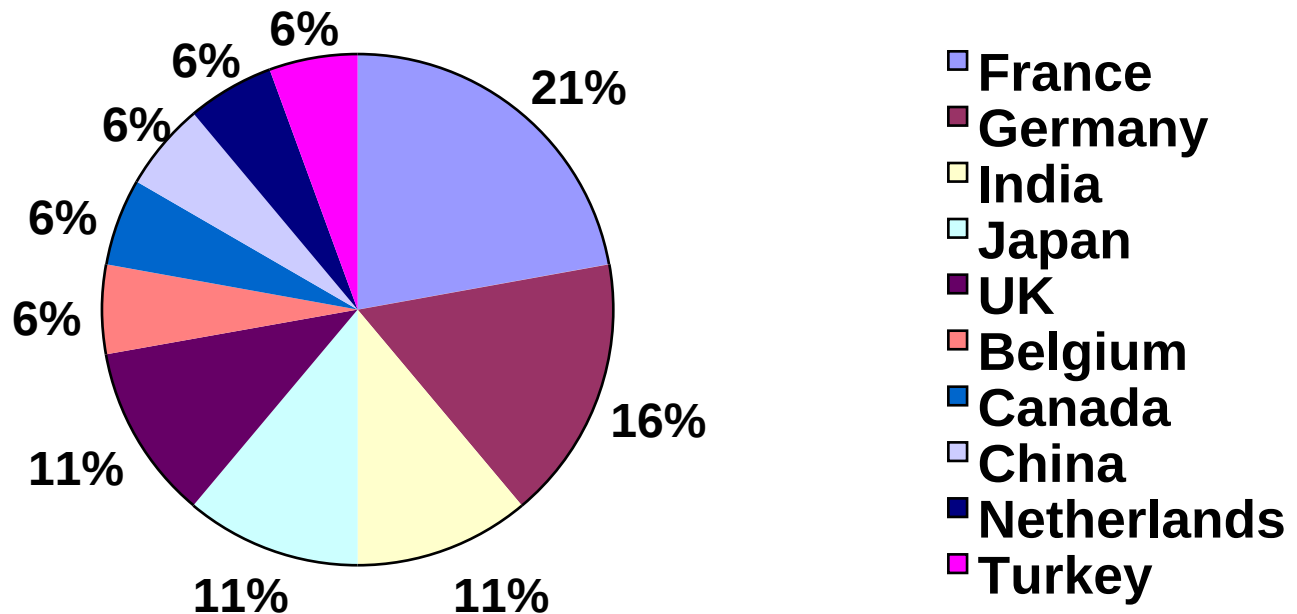
2004-2011: Participation

#	Year	Location	Participants
1	2004	Florence, Italy	25
2	2005	Edinburgh, UK	118
3	2006	Yokohama, Japan	103
4	2007	Vienna, Austria	73
5	2008	Washington, USA	82
6	2009	Lausanne, Switzerland	95
7	2010	Santa Barbara, USA	100
8	2011	Nara, Japan	116

Submissions

- Manuscripts submitted: 18
- Accepted submissions: 10

Submissions per country



Papers selection

- At least 3 reviewers per paper
- At least 5 reviewers for papers submitted by the program committee
- 1 week of discussions following the acceptance of reviews
- 68 reviews in total
- 45 discussions

Participants

- Japan 41
- France 23
- Germany 11
- USA 9
- The Netherlands 6
- Belgium, Korea 4
- Iran, Singapore 3
- Canada, Israel, Italy, Sweden 2
- India, Switzerland, Turkey 1

Program co-chairs:

Junko Takahashi

NTT Information
Laboratories, Tokyo,
Japan

Sylvain Guilley

Telecom ParisTech,
Paris, France

Program committee:

- *Guido Bertoni, ST Microelectronics, Italy*
- *Wieland Fischer, Infineon Technologies, Germany*
- *Christophe Giraud, Oberthur Technologies, France*
- *Helena Handschuh, K.U.Leuven, Belgium & Intrinsic-ID Inc., USA*
- *Naofumi Homma, Tohoku University, Japan*
- *Marc Joye, Technicolor, France*
- *Ramesh Karri, Polytechnic University, USA*
- *Régis Leveugle TIMA, France*
- *Debdeep Mukhopadhyay, IIT Kharagapur, India*
- *Gerardo Pelosi, Politecnico di Milano, Italy*
- *Denis Real, Ministry of Defense, France*
- *Kazuo Sakiyama, University of Electro Communication, Japan*
- *Jörn-Marc Schmidt, Technische Universität Graz, Austria*
- *Sergei Skorobogatov, University of Cambridge, UK*
- *Francois-Xavier Standaert, Univ. Catholique de Louvain, Belgium*
- *Michael Tunstall, University of Bristol, UK*
- *Ingrid Verbauwhede, Katholieke Universiteit Leuven, Belgium*

Invited talks chair:

David Naccache

École Normale
Supérieure de Paris,
France

Special Thanks

Local arrangements provided by

- Tetsuya Izu, Fujitsu
- Yumi Sakemi, Fujitsu
- Junko Takahashi, NTT Information Laboratories

09:09-09:15	Welcome and Opening Remarks <i>Israel Koren, Luca Breveglieri</i>
09:15-09:55	1st Keynote Talk: <i>Chair: Christophe Giraud</i> The Fault Attack Jungle – A Classification Model to Guide You <i>Ingrid Verbauwhede, Joern-Marc Schmidt and Dusko Karaklajic</i>
09:55-10:45	Session 1: Fault attacks on elliptic curves <i>Chair: Naofumi Homma</i> 1. Fault Sensitivity Analysis Against Elliptic Curve Cryptosystems <i>Hikaru Sakamoto, Yang Li, Kazuo Ohta and Kazuo Sakiyama</i> 2. A Cost-Effective FPGA-based Fault Simulation Environment <i>Angelika Janning, Johann Heyszl, Frederic Stumpf and Georg Sigl</i>
10:45-11:10	Coffee break
11:10-12:00	Session 2: Differential fault attacks <i>Chair: Francesco Regazzoni</i> 1. A Differential Fault Analysis on AES Key Schedule using Single Fault <i>Sk Subidh Ali and Debdeep Mukhopadhyay</i> 2. From AES-128 to AES-192 and AES-256: How to Adapt Differential Fault Analysis Attacks <i>Noémie Floissac and Yann L'Hyver</i> 3. Differential Fault Analysis on the SHA1 compression function <i>Ludger Hemme and Lars Hoffmann</i>

12:25-13:40	Lunch
13:40-14:20	2nd Invited Talk: <i>Chair: Guido Bertoni</i> Fault Injection, a Fast Moving Target in Evaluations <i>Rob Bekkers and Hans König</i>
14:20-15:10	Session 3: Algebraic fault detection <i>Chair: Wieland Fischer</i> 1. On Protecting Cryptographic Applications against Fault Attacks using Residue Codes <i>Kazim Yumbul, Serdar S. Erdem and Erkey Savas</i> 2. A High-Performance Fault Diagnosis Approach for the AES SubBytes utilizing Mixed Bases <i>Mehran Mozaffari-Kermani and Arash Reyhani-Masoleh</i>
15:10-15:35	Coffee break
15:35-16:50	Session 4: Fault injection in practice <i>Chair: Marc Joye</i> 1. Practical Optical Fault Injection on Secure Microcontrollers <i>J. G. J. van Woudenberg, M. F. Witteman and F. Menarini</i> 2. Local and Direct EM Injection of Power into CMOS Integrated Circuits <i>F. Poucheret, K. Tobich, M. Lisart, B. Robisson, L. Chusseau and P. Maurine</i> 3. An in-Depth and black-Box Characterization of the Effects of Clock Glitches on 8-bit MCUs <i>Josep Balasch, Benedikt Gierlichs and Ingrid Verbauwhede</i>
16:50-17:00	Closing remarks and Farewell